S	ear	ch	Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/669,710	KANNO ET AL.	
Examiner	Art Unit	
Baotran N. To	2135	

	SEAR	CHED	
Class	Subclass	Date	Examiner
726	22-25	10/18/2007	вт
709	223-225	10/18/2007	ВТ
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST SEARCH (USPAT; USPGPUB; EPO; JPO; DERWENT; IBM_TDB)	10/18/2007	ВТ	
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